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*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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X	Huang-S.Y. et al. "Fault Simulation based Design Error Diagnosis for Sequential Circuits" ACM June 1998, pp.632-637	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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	V	Fujita et al., "Methods of Automatic Design Error Correction in Sequential Circuits" IEEE September 1993. pp.76-80.
	W	Chung et al." Diagnosis and Correction of Logic Design Errors in Digital Circuits" IEEE June 1993, pp.503-508.
	X	Kuo et al., "Locating Logic Design Errors via Test Generation and Don't-Care Propagation" IEEE September 1992, pp.466-471.

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V		Tamura-K.A., "Locating Functional Errors in Logic Circuits" ACM June 1989, pg.185-191.
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